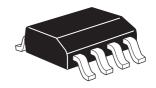


Complementary 30V enhancement mode MOSFET

Summary

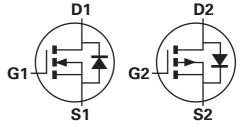
N-Channel = $V_{(BR)DSS}$ = 30V : $R_{DS(on)}$ = 0.025 Ω ; I_D = 7.6A

P-Channel = $V_{(BR)DSS}$ = -30V : $R_{DS(on)}$ = 0.035Ω; I_D = -6.3A



Description

This new generation of trench MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.



Q1 N-Channel

Q2 P-Channel

Features

- · Low on-resistance
- · Fast switching speed
- · Low threshold
- · Low gate drive
- · Low profile SOIC package

Applications

- Motor Drive
- LCD backlighting

Ordering information

Device	Reel size	Tape width	Quantity	
	(inches)	(mm)	per reel	
ZXMC3A18DN8TC	13	12	2500	

Device marking

ZXMC 3A18

Absolute maximum ratings

Parameter	Symbol	N-channel	P-channel	Unit
Drain-source voltage	V_{DSS}	30	-30	V
Gate-source voltage	V_{GS}	±20	±20	V
Continuous drain current (V _{GS} = 10V; T _{amb} =25°C) ^{(b)(d)}	I _D	7.6	-6.3	Α
(V _{GS} = 10V; T _{amb} =70°C) ^{(b)(d)}		6.1	-5.0	
(V _{GS} = 10V; T _{amb} =25°C) ^{(a)(d)}		5.8	-4.8	
Pulsed drain current ^(c)	I _{DM}	37	-30	Α
Continuous source current (body diode)(b)	I _S	3.6	3.2	Α
Pulsed source current (body diode)(c)	I _{SM}	37	30	Α
Power dissipation at T _{amb} =25°C ^{(a)(d)}	P _D	1.2	25	W
Linear derating factor		10		mW/°C
Power dissipation at T _{amb} =25°C ^{(a)(e)}	P _D	1.8		W
Linear derating factor		14		mW/°C
Power dissipation at T _{amb} =25°C ^{(b)(d)}	P _D	2.	1	W
Linear derating factor		1	7	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to	+150	°C

Thermal resistance

Parameter	Symbol	Value	Unit
Junction to ambient ^{(a)(d)}	$R_{\Theta JA}$	100	°C/W
Junction to ambient ^{(a)(e)}	$R_{\Theta JA}$	70	°C/W
Junction to ambient ^{(b)(d)}	$R_{\Theta JA}$	60	°C/W

NOTES:

⁽a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

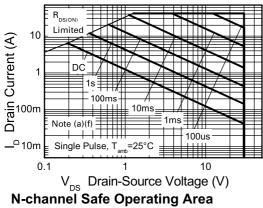
⁽b) For a device surface mounted on FR4 PCB measured at t \leq 10 sec.

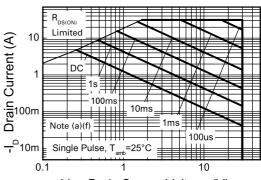
⁽c) Repetitive rating - pulse width limited by maximum junction temperature. Pulse width 300µs, d<= 0.02. Refer to transient thermal impedance graph.

⁽d) For device with one active die.

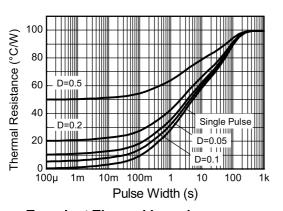
⁽e) For device with two active die running at equal power.

Characteristics

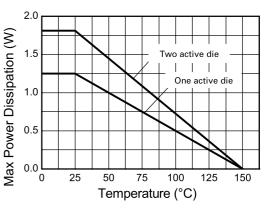




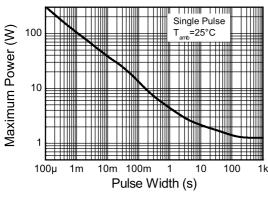
 ${}^{-}\!V_{\scriptscriptstyle DS}$ Drain-Source Voltage (V) P-channel Safe Operating Area



Transient Thermal Impedance



Derating Curve



Pulse Power Dissipation

N-channel Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

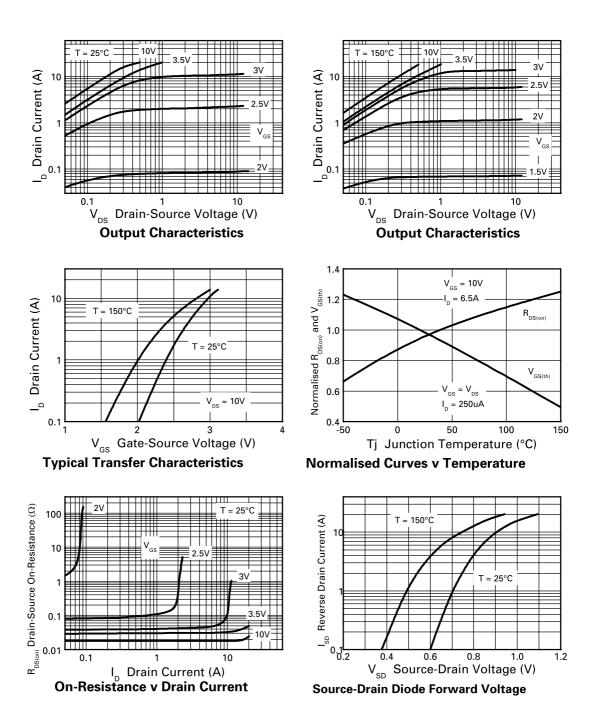
Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static			•	•		
Drain-source breakdown voltage	V _{(BR)DSS}	30			V	I _D = 250μA, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}			0.5	μΑ	V _{DS} =30V, V _{GS} =0V
Gate-body leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V
Gate-source threshold voltage	V _{GS(th)}	1.0			V	I _D = 250μA, V _{DS} =V _{GS}
Static drain-source on-state resistance (*)	R _{DS(on)}			0.025 0.030	Ω	V_{GS} = 10V, I_{D} = 5.8A V_{GS} = 4.5V, I_{D} = 5.3A
Forward transconductance(*)(‡)	9 _{fs}		17.5		S	$V_{DS} = 15V, I_{D} = 5.8A$
Dynamic ^(‡)	l					
Input capacitance	C _{iss}		1800		pF	V _{DS} = 25V, V _{GS} =0V
Output capacitance	C _{oss}		289		pF	f=1MHz
Reverse transfer capacitance	C _{rss}		178		pF	
Switching (†) (‡)	•	•		•		
Turn-on-delay time	t _{d(on)}		5.5		ns	V _{DD} = 15V, I _D = 6A
Rise time	t _r		8.7		ns	$R_G \cong 6.0\Omega$, $V_{GS} = 10V$
Turn-off delay time	t _{d(off)}		33		ns	
Fall time	t _f		8.5		ns	
Gate charge	Q_g		19.4		nC	V_{DS} = 15V, V_{GS} = 5V I_{D} = 3.5A
Total gate charge	Qg		36		nC	V _{DS} = 15V, V _{GS} = 10V
Gate-source charge	Ogs		5.5		nC	I _D = 3.5A
Gate drain charge	Q _{gd}		7.0		nC	
Source-drain diode				•		
Diode forward voltage ^(*)	V_{SD}			0.95	٧	T_j =25°C, I_S = 6A, V_{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		20.5		ns	T _j =25°C, I _S = 6A,
Reverse recovery charge ^(‡)	Q_{rr}		41.5		nC	di/dt=100A/μs

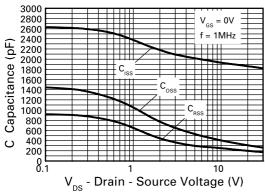
NOTES:

^(*) Measured under pulsed conditions. Pulse width ${\leq}300\mu s;$ duty cycle ${\leq}2\%.$

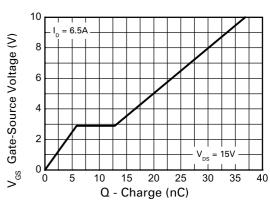
^(†) Switching characteristics are independent of operating junction temperature.

^(‡) For design aid only, not subject to production testing.

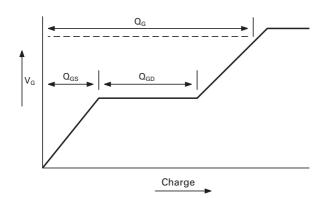




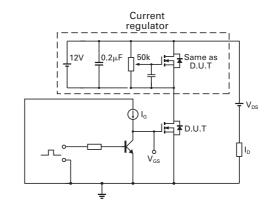
Capacitance v Drain-Source Voltage



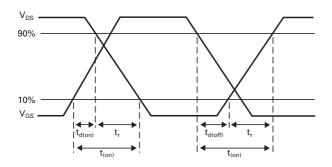
Gate-Source Voltage v Gate Charge



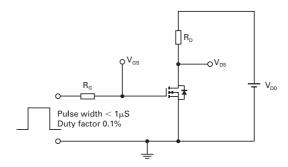
Basic gate charge waveform



Gate charge test circuit



Switching time waveforms



Switching time test circuit

P-channel Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

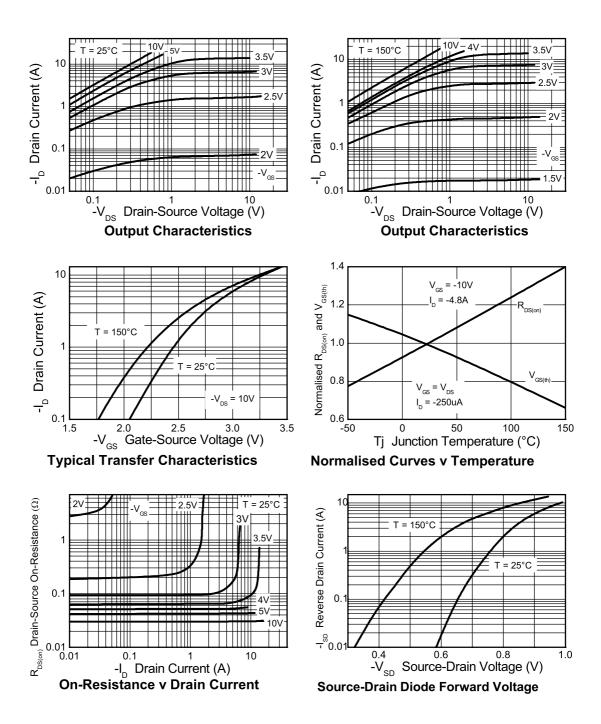
Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						,
Drain-source breakdown voltage	V _{(BR)DSS}	-30			V	I _D = -250μA, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}			-1.0	μΑ	V _{DS} = -30V, V _{GS} =0V
Gate-body leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V
Gate-source threshold voltage	V _{GS(th)}	-1.0			V	I_D = -250 μ A, V_{DS} = V_{GS}
Static drain-source on-state resistance (*)	R _{DS(on)}			0.035 0.050	W	V_{GS} = -10V, I_{D} = -4.8A V_{GS} = -4.5V, I_{D} = -4.0A
Forward transconductance(*)(‡)	9 _{fs}		8.6		S	V _{DS} = -15V, I _D = -4.8A
Dynamic ^(‡)						
Input capacitance	C _{iss}		1603		рF	V _{DS} = -15V, V _{GS} =0V
Output capacitance	C _{oss}		434		рF	f=1MHz
Reverse transfer capacitance	C _{rss}		388		pF	
Switching ^{(†) (‡)}						
Turn-on-delay time	t _{d(on)}		4.8		ns	V _{DD} = -15V, I _D = -1A
Rise time	t _r		9.5		ns	$R_{G} @ 6.0\Omega, V_{GS} = 10V$
Turn-off delay time	t _{d(off)}		60		ns	
Fall time	t _f		38		ns	
Gate charge	Q_g		25		nC	V_{DS} = -15V, V_{GS} = -5V I_{D} = -4.8A
Total gate charge	Q_g		45		nC	V _{DS} = -15V, V _{GS} = -10V
Gate-source charge	Q_{gs}		5.1		nC	I _D = -4.8A
Gate drain charge	Q _{gd}		11.5		nC	
Source-drain diode						
Diode forward voltage ^(*)	V _{SD}		0.82	-0.95	V	T _j =25°C, I _S = -3.7 V _{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		32.5		ns	T _j =25°C, I _S = -2.2,
Reverse recovery charge ^(‡)	Q _{rr}		18.4		nC	di/dt=100A/μs

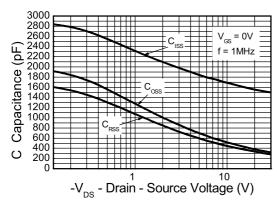
NOTES:

^(*) Measured under pulsed conditions. Pulse width ${\leq}300\mu s$; duty cycle ${\leq}2\%.$

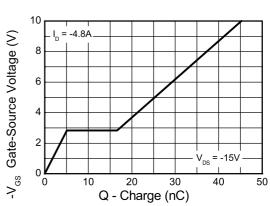
^(†) Switching characteristics are independent of operating junction temperature.

^(‡) For design aid only, not subject to production testing.

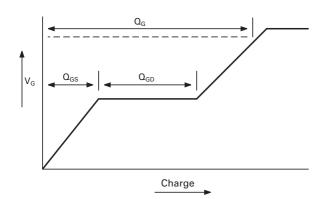




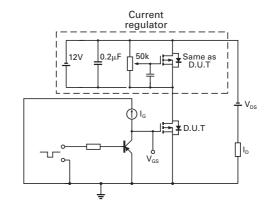
Capacitance v Drain-Source Voltage



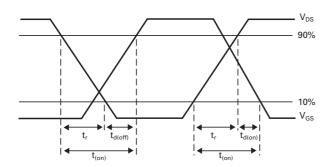
Gate-Source Voltage v Gate Charge



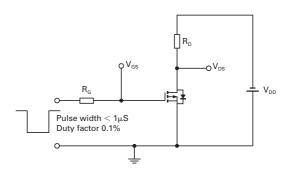
Basic gate charge waveform



Gate charge test circuit



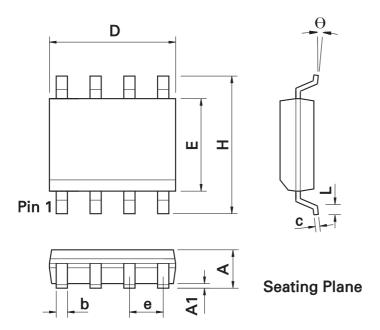
Switching time waveforms



Switching time test circuit

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Package outline - SO8



DIM	Inc	hes	Millin	neters	DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
Α	0.053	0.069	1.35	1.75	е	0.050 BSC		1.27 BSC	
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
Н	0.228	0.244	5.80	6.20	θ	0°	8°	0°	8°
Е	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	-	-

Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

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